

FORM PTO-1449 (Modified)  LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	ATTY. DOCKET NO. : YOR920030401US1	SERIAL NO.: CONFIRMATION NO. <b>10/665,092</b>
	APPLICANT: Chandramouli Visweswariah	
(Use several sheets if necessary)	FILING DATE: <b>9/18/3</b>	GROUP: <b>2825</b>

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
<b>WJ</b>	AA	5 5 0 8 9 3 7	4/10/1996	Abato, et al	364/488	GO6F 17/50	5/16/1993
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
AJ						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

<b>WP</b>	AK	"Explicit Computation of Performance as a Function of Process Variation", L. Scheffer, TAU'02, December 2-3, 2002, Monterey, California, USA
<b>WP</b>	AL	"Timing Yield Estimation from Static Timing Analysis", Anne Gattiker, Sani Nassif, Rashmi Dinakar, Chris Long. IEEE International Symposium on Quality Electronic Design, 2001
<b>WJ</b>	AM	"Fast Statistical Timing Analysis by Probabilistic Event Propagation", Jing-Jia Liou, Kwang-Ting Cheng, Sandip Kundu, Angela Krstic, DAC 2001, June 18-22, 2001, Las Vegas, Nevada, USA
<b>WP</b>	AN	"Statistical Timing for Parametric Yield Prediction of Digital Integrated Circuits" J.A. G. Jess, K. Kalafala, S.R. Naidu, R.H.J.M. Otten, C. Visweswariah, DAC 2003, June 2-6, 2003, Anaheim, California, USA

EXAMINER <b>WJ</b>	DATE CONSIDERED <b>1/19/6</b>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.